


<b>Search Notes</b>  	<b>Application/Control No.</b>  10617834	<b>Applicant(s)/Patent Under Reexamination</b>  WAKAYAMA ET AL.
	<b>Examiner</b>  Xavier Szewai Wong	<b>Art Unit</b>  2416

### SEARCHED

Class	Subclass	Date	Examiner
370	392, 419-421, 469 (updated 12.03.08)	12.03.08 (updated 04.22.09)	XSW (updated 12.03.08)
370	235-237	04.22.09	XSW

### SEARCH NOTES

Search Notes	Date	Examiner
updated EAST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (please see search history)	12.03.08 - updated 04.22.09	XSW (updated 04.22.09)
updated inventor and assignee search on EAST and PALM	updated 4.22.09	XSW (updated 04.22.09)

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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